## NSN 6625-01-419-8132

Semiconductor Device Test Set - Page 1 of 1



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Common test equipment

Inclosure Feature:

Multiple item w/housing

**Test Type For Which Designed:** 

Parameter charactization of semiconductor devices

**Purchase Description Identification:** 

1t110contract/f41608-94-c-0785

Shelf Life:

N/a

**Unit Of Measure:** 

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Demilitarization:

Yes - demil/mli

Fiig:

T228-a